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Quote

Entwining physics and electronics, I explore and design unconventional computational architectures that can transcend computing to an open, interactive and evolving system that can solve a diverse range of problems.

Research outputs

A CMOS-compatible oscillation-based VO_2 Ising machine solver
Maher, O. (Corresponding author), Jiménez, M., Delacour, C., Harnack, N., Núñez, J., Avedillo, M. J., Linares-Barranco, B., Todri-Sanial, A., Indiveri, G. & Karg, S. (Corresponding author), Dec 2024, In: Nature Communications. 15, 1, 11 p., 3334.

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Multimodal Processing at the Edge
Edgar Leonard Marvin Luhulima, E., Sabo, F. & Todri-Sanial, A., 2024.

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A mixed-signal oscillatory neural network for scalable analog computations in phase domain
Delacour, C. (Corresponding author), Carapezzi, S., Boschetto, G., Abernot, M., Gil, T., Azemard, N. & Todri-Sanial, A., 1 Sept 2023, In: Neuromorphic Computing and Engineering. 3, 3, 30 p., 034004.

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